2SC5505

Silicon NPN epitaxial planar type

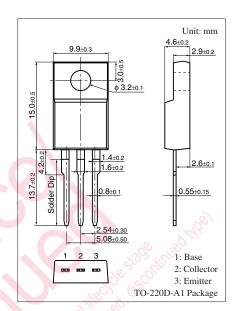
For power amplification

■ Features

- High-speed switching
- TO-220D built-in: Excellent package with withstand voltage 5 kV guaranteed

■ Absolute Maximum Ratings $T_C = 25$ °C

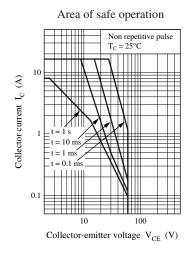
Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V _{CBO}	60	V	
Collector-emitter voltage (Base open)	V _{CEO}	60	V	
Emitter-base voltage (Collector open)	V_{EBO}	5	V	
Collector current	I_C	8	A	
Peak collector current	I_{CP}	16	A	
Collector power dissipation	P _C	20	W	
$T_a = 25^{\circ}C$		2.0		
Junction temperature	T_j	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

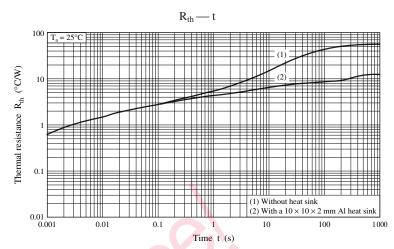


■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = 10 \text{ mA}, I_B = 0$	60			V
Collector-base cutoff current (Emitter open)	I _{CBO}	$V_{CB} = 60 \text{ V}, I_{E} = 0$			100	μΑ
Collector-emitter cutoff current (Base open)	I_{CEO}	$V_{CE} = 60 \text{ V}, I_{B} = 0$			100	μΑ
Forward current transfer ratio	h _{FE1}	$V_{CE} = 2 \text{ V}, I_{C} = 1 \text{ A}$	80		280	_
	h _{FE2}	$V_{CE} = 2 \text{ V}, I_{C} = 5 \text{ A}$	50			
Collector-emitter saturation voltage	V _{CE(sat)}	$I_C = 5 \text{ A}, I_B = 0.25 \text{ A}$			1.2	V
Base-emitter saturation voltage	V _{BE(sat)}	$I_C = 5 \text{ A}, I_B = 0.25 \text{ A}$			1.7	V
Turn-on time	t _{on}	I _C = 4 A		0.2	0.5	μs
Storage time	t _{stg}	$I_{B1} = 400 \text{ mA}, I_{B2} = -400 \text{ mA}$		0.5	1.0	μs
Fall time	$t_{\rm f}$	$V_{CC} = 50 \text{ V}$		0.10	0.15	μs

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.





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